News Release

October 2nd, 2013

Advantest Europe GmbH
Stefan-George-Ring 2
81929 Munich
Germany

ADVANTEST®

For Immediate Release

Advantest to Showcase SOC, Nanotech and Cloud Testing Platforms at SEMICON Europa 2013

Booth to Feature New, Leading-Edge CloudTesting™ Solution

Munich, Germany, October 2nd, 2013 - Leading semiconductor test equipment supplier Advantest Corporation (TSE: 6857, NYSE: ATE) will showcase its suite of semiconductor solutions, ranging from nanotechnology electron beam (EB) lithography to automatic test equipment and cloud testing services at the SEMICON Europa 2013 trade show, stand #1.207, Hall 1, October 8-10 in Dresden, Germany.

Visitors will learn how to lower the cost of test and boost productivity for a variety of applications, including system-on-chip (SOC) and system-in-package (SiP) devices as well as advanced wafer-level chip-scale packages (WLCSPs). Additionally, Advantest will highlight an industry-first cloud testing solution ideal for semiconductor design, electronic component R&D, prototype evaluation, failure analysis and academic research. The company will also display next-generation nanotechnology EB lithography for nano-patterning and defect review as well as its multi-vision 3D metrology technologies.

“For the first time at SEMICON Europa, Advantest will have dedicated displays for its nanotech and cloud testing technologies,” said Josef Schraetzenstaller, managing director and CEO of Advantest Europe. “These new additions align with the company’s strategic, proactive expansion into new markets, while continuing to invest in ATE solutions.”

In collaboration with the SEMICON Europa trade show, Advantest will present a number of technical papers on its cloud testing services, 3D metrology, MEMs, automotive and test leadership at EMTC and the Tech Arena:

EMTC, Tuesday, October 8

- 13:35: “Automotive Single Insertion Multi-Temperature KGD Test Solution,” by Gary Fleeman
- 15:10: “An Introduction to CloudTesting™, Making Chip Test Available for Everyone,” by Manabu Kimura
- 16:30: Panel Discussion: “Is Test Becoming a Commodity?” with Michael Stichlmair

EMTC, Wednesday, October 9

- 11:00: Panel Discussion: “How Do We Leverage EU Leadership in MEMS Test into Other Areas?” with Adriano Mancosu

TechArena, Wednesday, October 9

- 13:15: “An Introduction to CloudTesting^{TM}, Making Chip Test Available to Everyone,” by Manabu Kimura

TechArena, Thursday, October 10

- 14:00: “Introduction of Novel 3D Metrology Tool for Leading Edge Devices,” by Kazuhiro Arakawa.

About Advantest

A world-class technology company, Advantest is the leading producer of automatic test equipment (ATE) for the semiconductor industry and a premier manufacturer of measuring instruments. Its leading-edge products are integrated into the most advanced semiconductor production lines in the world. The company also focuses on R&D for emerging markets that benefit from advancements in nanotech and terahertz technologies, and has introduced multi-vision metrology scanning electron microscopes essential to photo mask manufacturing, and 3D imaging analysis tools to the pharmaceutical and transportation industries. Founded in Tokyo in 1954, Advantest established its first subsidiary in 1982, in the USA, and now has subsidiaries worldwide. More information is available at www.advantest.de.

For further information please contact:

Corporate Communications

Email: info@eu.advantest.com